PITOTAL SYSTEMS

Improving Etch Tool Performance Using an In Situ Gas Flow Monitoring (GFM) & Control System

> Kelly McDonough PAG, August 12th, 2010

Presentation Based on Joint Article with IBM

Mathors

- Kevin Boyd, IBM
- Muk Venkatesh, Pivotal Systems
- Joe Monkowski, Pivotal Systems

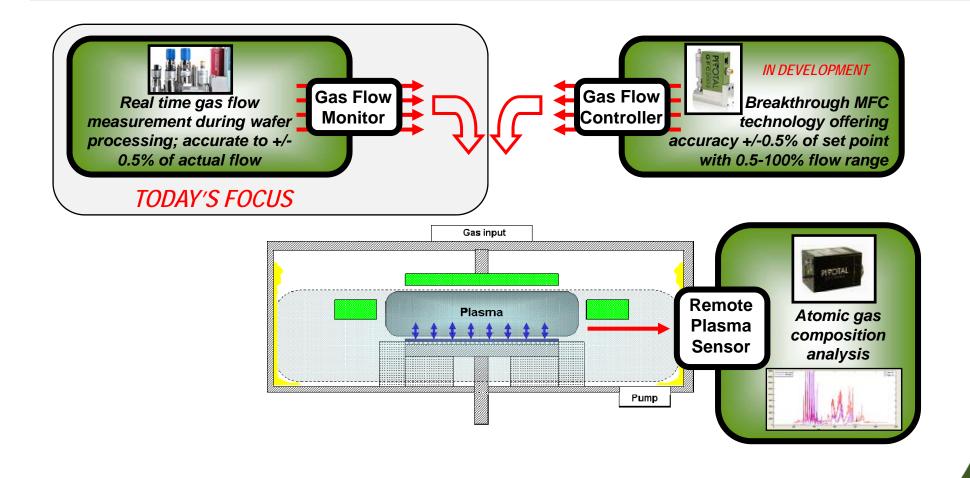
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Pivotal Systems – In Situ Monitoring & Control of Key Parameters for Wafer Processing



Increasing Yield, Extending Equipment & Reducing COO

Demands on Gas Flow Delivery Systems Increasing

Smaller dimensions & features

- Gas flow rates as low as 2sccm
- Accuracy & repeatability of flow to set point as low as ±0.5%

Continuous plasma processing (for RIE defect reduction)

- No gas flow stabilization steps
- Repeatability of gas flow transients and settling times critical for optimized yield parameters (e.g., CD)

Gas Flow Delivery Systems Struggling to Keep Up

Best-in-class MFCs

- ±1% of set point
- Typically >±1% at low flow (unless special low flow MFCs are used)
- Run to run variability in transients and settling times

Existing MFC flow verification / calibration approaches

- Only off-line measurements (~2-3% of tool availability), no real-time
- Accuracy ranges from ±1% to as high as ±5%

While power delivery, chamber temperature and pressure are monitored / controlled with tight accuracy, gas flow delivery systems are struggling to keep up

Pivotal's Gas Flow Monitoring (GFM) System

- <u>Real-time, In-situ</u>: Gas flow monitoring during wafer processing
- First Principles Measurement: Rate of pressure drop
- High Accuracy and Repeatability: Better than ±0.5% of flow
- Quick Measurement: Less than 5 seconds (200ms for transients)
- Easy Installation: Standard wetted parts used in gas sticks today

Significant benefits

- Identify out-of-spec MFC drifts and transients
- Eliminate tool downtime from off-line MFC calibration
- Reduce MFC troubleshooting costs, eliminating "no fault" found MFC FA
- Avoid costly wafer scrap events due to gas flow variations
- Improve chamber matching and device yield

Existing Gas Flow Verification Solutions

Existing solutions, often executed once per week or less, include:

- Chamber rate of rise
 - Typically ±3-5% (to do it right takes a long time for temp stabilization)
- **Flow path diversion methods such as the MKS GBROR® or Tru-Flo® Mass Flow Verifier**
 - Typically ±1% accuracy
- Molbloc (Test Lab Standard)
 - Typically ±0.2% accuracy

MKS GBROR®

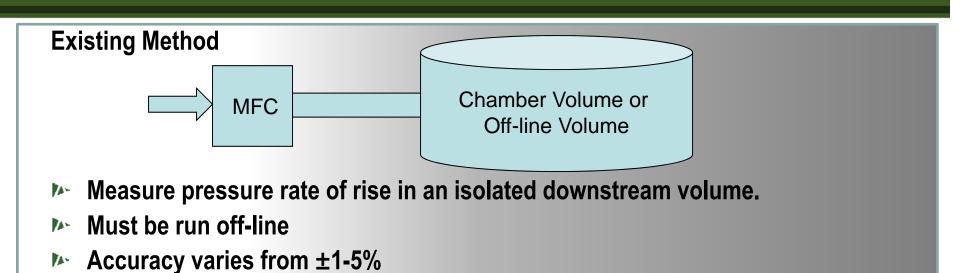


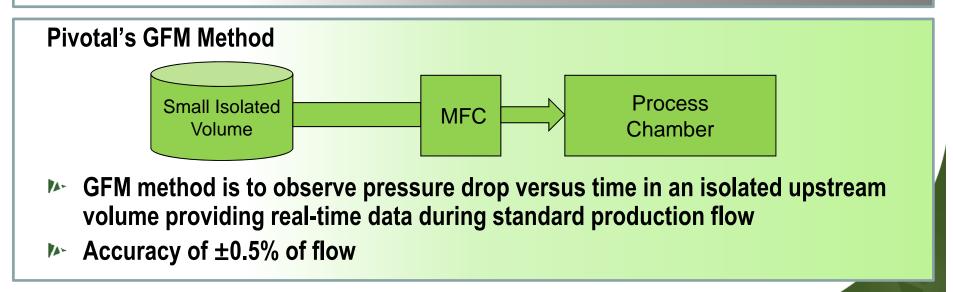


De facto Industry Standard

- Typically 60 seconds per measurement
- Flow path diversion measurement
- Loss of wafer processing time

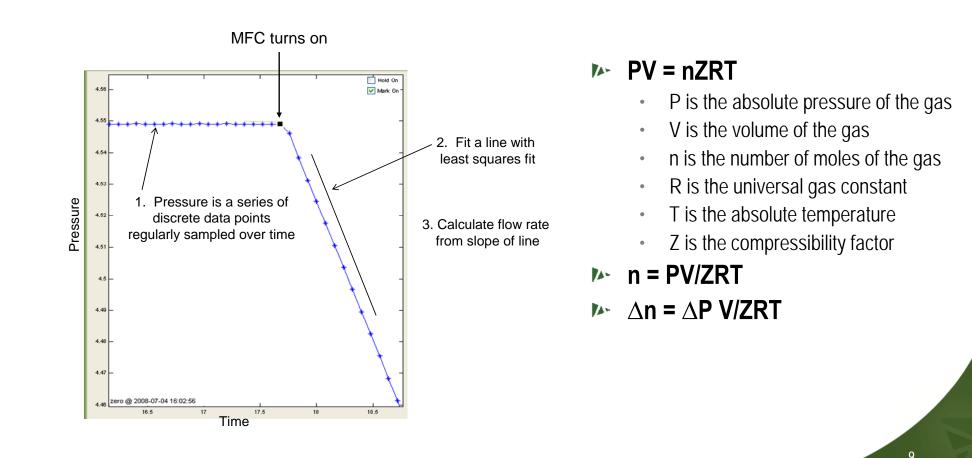
Pivotal's Real-Time GFM Method



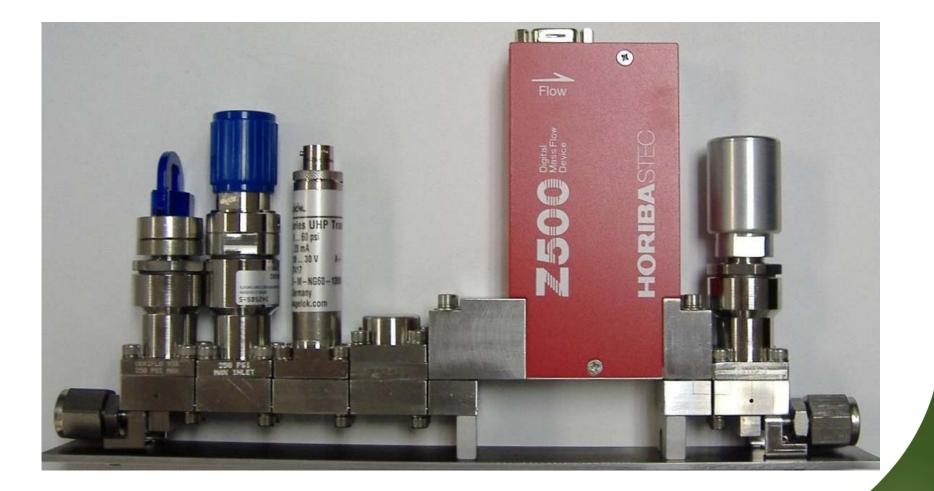


Operating Principle - Ideal Gas Law

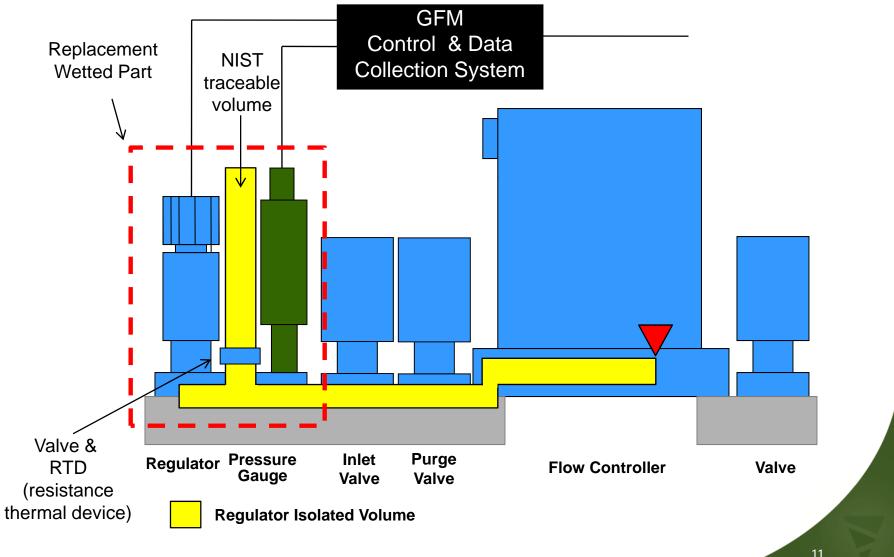
From the Ideal Gas Law, we know pressure in an isolated volume will decrease linearly with time when the flow rate out of the fixed volume is constant



Typical Gas Stick



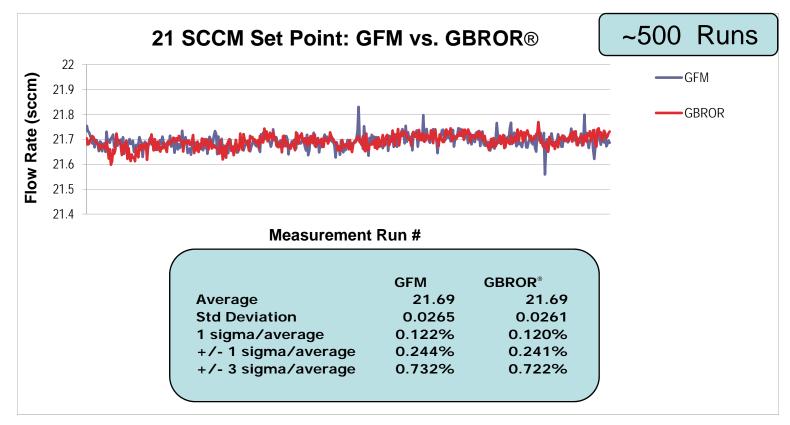
Pivotal's Solution: Gas Flow Monitor (GFM)



Pivotal Data for GFM

- Accuracy & Repeatability
- Production Data
- Market Transient Studies

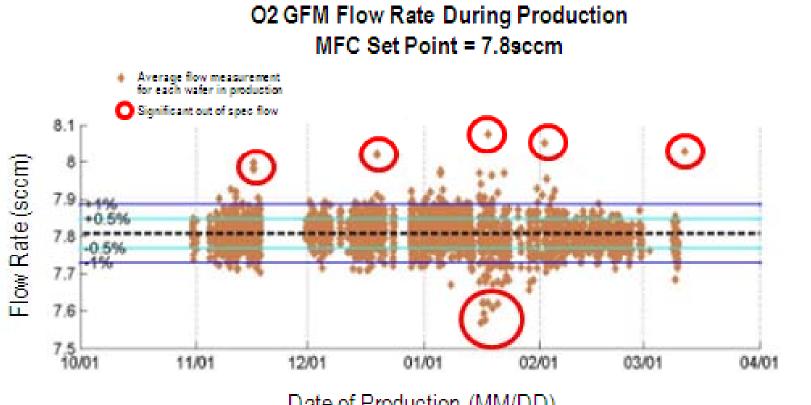
Excellent Agreement between GFM & MKS GBROR[®]



Measurement techniques differ between GFM & GBROR®

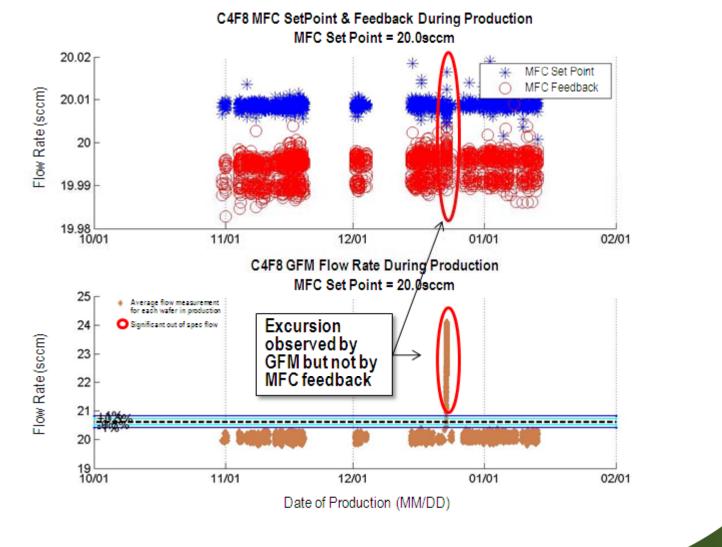
- GBROR[®] measures average flow rate over 1 minute
- GFM measures flow rate in the initial 5 seconds of gas flow

Example Production Data – O2 MFC

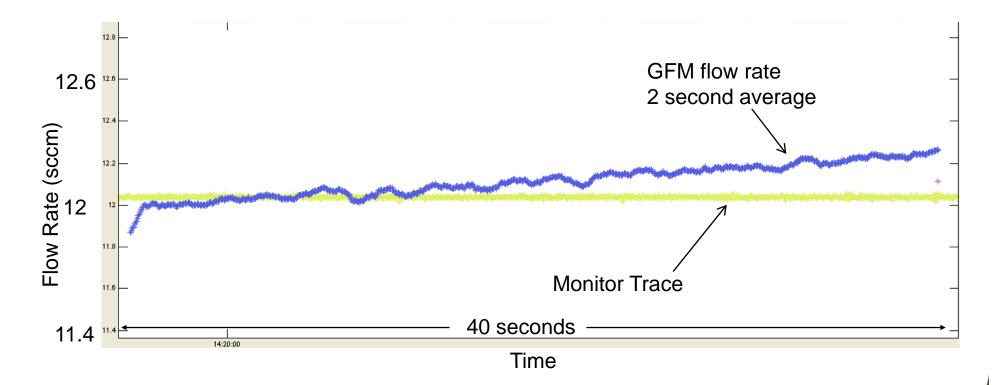


Date of Production (MM/DD)

Example Production Data – C4F8 MFC

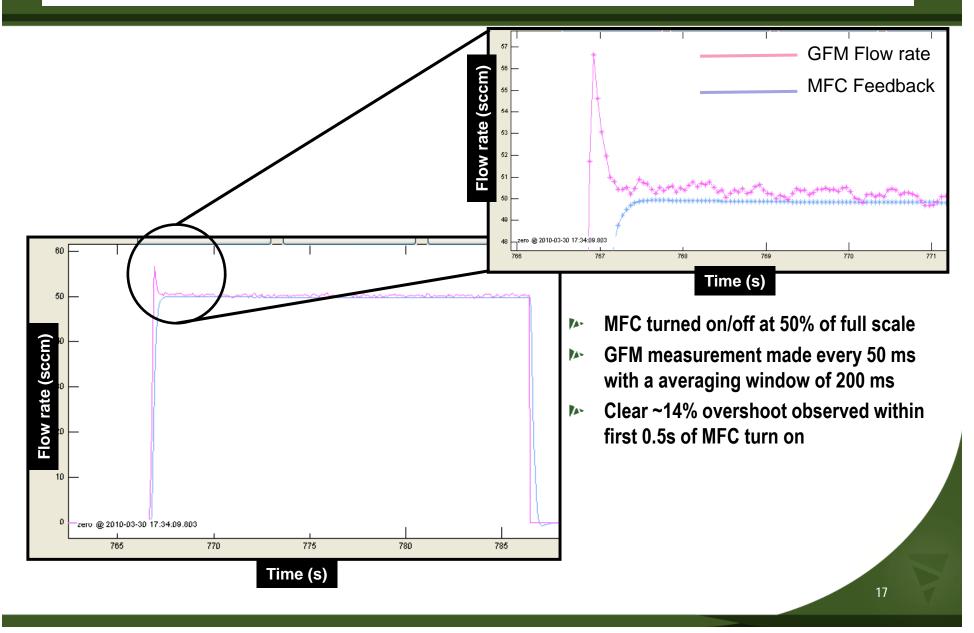


Example Production Data – HBr MFC

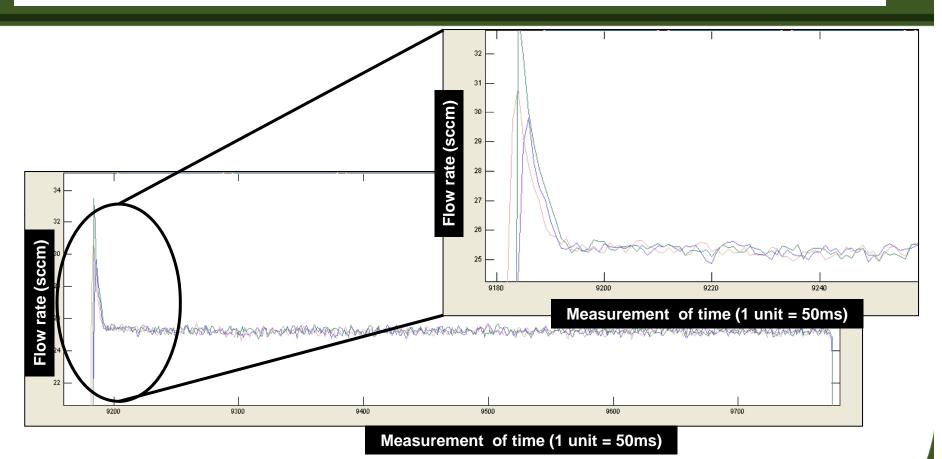


- Example of a MFC with a set point that is drifting over time.
- GFM measurement made every 50 ms catches the drift
- More than the customer tried to recalibrate this MFC but it failed and was replaced
- If MFC were tested by GBROR which averages data over ~1min it would pass!!

Transients – On/Off Square Wave (50% Full Scale)



Transients – On/Off Overlay (25% Full Scale)



- MFC turned on/off at 25% of full scale and cycled ~160 times
- GFM measurement made every 50 ms with a averaging window of 200 ms
- Momentum Three runs selected for display, from beginning, middle and end of cycling
- Overshoot ranging from ~15%-30% observed between runs

Control Schemes using GFM

When an MFC is observed to be out of flow specification during wafer processing, automatic control options include:

- Alerting equipment engineer
- Stopping wafer processing- operator intervention
 - Recalibrating troubled MFC
 - Swap MFC
- Changing MFC set point for subsequent wafer (feedback control loop)

Control Schemes using GFM

Without Pivotal GFM

Best-in-class MFCs

- ±1% of set point
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- Run to run variability in transients and settling times

Existing MFC flow verification / calibration approaches

- Only off-line measurements (~2-3% of tool availability), no real-time
- Accuracy ranges from ±1-5%

With Pivotal GFM

- Know what your MFC is running
 - Accuracy & Repeatability to ±0.5%
 - 50ms sampling for Transients
- Take action in real time
- Minimize service and diagnostic downtime

Pivotal Systems 4683 Chabot Drive Ste 300 Pleasanton, CA 94588 (925)924-1480 <u>info@pivotalsys.com</u> <u>www.pivotalsys.com</u>

